IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No.	10/632,273
Filing Date	
Inventor	
Assignee	Micron Technology, Inc.
Group Art Unit	
Examiner	
Attorney's Docket No	Ml22-2379
Customer No	021567
Title: Method and Apparatus for Testing Semiconduct	or Circuitry for Operability and
Method of Forming Apparatus for Testing Semicon	nductor Circuitry for Operability

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References - - See attached Form PTO-1449

The attached Form PTO-1449 is submitted In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the references listed on the attached Form PTO-1449. Pursuant to Federal Register Vol. 69, No. 182, pg. 56542 (September 21, 2004), no copies of any cited U.S. patents or U.S. published applications are included herewith. Copies of all other cited art references, if any, are attached. No admission is made regarding whether the submitted references are prior art.

This is a second submission of this Supplemental Information Disclosure Statement and Form PTO-1449 (originally filed April 16, 2007) since the first submission was inadvertently filed with out a proper signature.

The fee for submission of this Supplemental Information Disclosure Statement was paid on April 16, 2007, therefore it is believed that no fees are due at this time. However, in the event that a fee is required for filing this Information Disclosure Statement, please charge the fee specified under 37 C.F.R. §1.17(p) to Deposit Account No. 23-0925.

Citation of this reference is respectfully requested.

Respectfully submitted,

Date: 4-18-07

D. Brent Kenady Reg. No. 40,045 Form PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. MI22-2379

SERIAL NO. 10/632,273

LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)

APPLICANT
Warren M. Farnworth

FILING DATE
July 31, 2003

GROUP **2829**

U.S. PATENT DOCUMENTS

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	AM	3-69131	8/1998	Japan			X	
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.